Sept 2017

ON Semiconductor®



FDS86242

N-Channel PowerTrench[®] MOSFET 150 V, 4.1 A, 67 m Ω

Features

- Max $r_{DS(on)}$ = 67 m Ω at V_{GS} = 10 V, I_D = 4.1 A
- Max r_{DS(on)} = 98 mΩ at V_{GS} = 6 V, I_D = 3.3 A
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability in a widely used surface mount package
- 100% UIL Tested
- RoHS Compliant

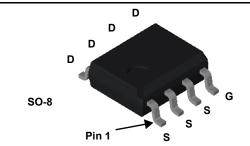


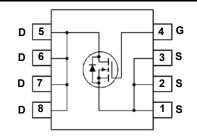
General Description

This N -Channel MOSFET is produced using ON Semiconductor's advanced Power T rench[®] process that has been optimized for $r_{DS(on)}$, switching per formance and ruggedness.

Applications

- DC/DC converters and Off-Line UPS
- Distributed Power Architectures and VRMs
- Primary Switch for 24V and 48V Systems
- High Voltage Synchronous Rectifier





MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Para	meter		Ratings	Units
V _{DS}	Drain to Source Voltage			150	V
V _{GS}	Gate to Source Voltage			±20	V
ID	Drain Current -Continuous			4.1	^
	-Pulsed			20	— A
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	40	mJ
P _D	Power Dissipation	T _C = 25 °C	(Note 1)	5.0	w
	Power Dissipation	T _A = 25 °C	(Note 1a)	2.5	vv
T _J , T _{STG}	Operating and Storage Junction Tempe	erature Range		-55 to +150	°C

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	(Note 1)	25	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	C/W

Package Marking and Ordering Information

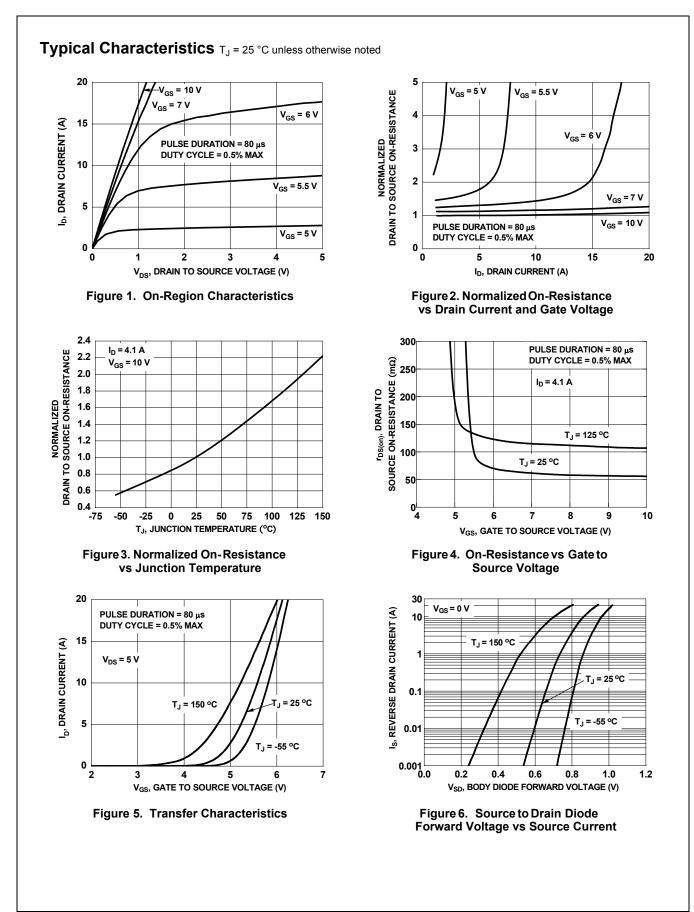
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS86242	FDS86242	SO-8	13 "	12 mm	2500 units

cteristics Drain to Source Breakdown Voltage Breakdown Voltage Temperatur Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current cteristics	$I_D = 250 \ \mu A, V_{GS} = 0 \ V$ $I_D = 250 \ \mu A, referenced to 25 \ ^C$ $V_{DS} = 120 \ V, V_{GS} = 0 \ V$	150			
Breakdown Voltage Temperatur Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current	I_D = 250 µA, referenced to 25 °C V _{DS} = 120 V, V _{GS} = 0 V	150			
Breakdown Voltage Temperatur Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current	I_D = 250 µA, referenced to 25 °C V _{DS} = 120 V, V _{GS} = 0 V				V
Gate to Source Leakage Current			104		mV/°C
				1	μA
stariation	V_{GS} = ±20 V, V_{DS} = 0 V			±100	nA
Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250 μA	2	3.5	4	V
Gate to Source Threshold Voltage	$I_D = 250 \ \mu$ A, referenced to 25 °C		-10		mV/°C
	V _{GS} = 10 V, I _D = 4.1 A		56.3	67	
Static Drain to Source On Resistance	V _{GS} = 6 V, I _D = 3.3 A		73.8	98	mΩ
	V_{GS} = 10 V, I_{D} = 4.1 A, T_{J} = 125 °C		107	126	
Forward Transconductance	V _{DS} = 10 V, I _D = 4.1 A		11		S
Characteristics					
			570	760	pF
					pF
	f = 1MHz		2.9	5	pF
Gate Resistance			0.5		Ω
Characteristics					
Turn-On Delay Time					
			79	16	ns
	V		7.9	16 10	ns
Rise Time	$V_{DD} = 75 \text{ V}, \text{ I}_{D} = 4.1 \text{ A},$ $V_{CS} = 10 \text{ V}, \text{ R}_{CEN} = 6 \Omega$		1.5	10	ns
Rise Time Turn-Off Delay Time	V_{DD} = 75 V, I _D = 4.1 A, V _{GS} = 10 V, R _{GEN} = 6 Ω		1.5 13	10 23	ns ns
Rise Time Turn-Off Delay Time Fall Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		1.5 13 2.8	10 23 10	ns ns ns
Rise Time Turn-Off Delay Time Fall Time Total Gate Charge	$V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$ $V_{GS} = 0 \text{ V to } 10 \text{ V}$		1.5 13 2.8 8.9	10 23 10 13	ns ns ns nC
Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge	$V_{GS} = 10 \text{ V}, $		1.5 13 2.8 8.9 4.9	10 23 10	ns ns ns nC nC
Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Charge	$V_{GS} = 10 \text{ V}, \text{R}_{GEN} = 6 \Omega$ $V_{GS} = 0 \text{ V to } 10 \text{ V}$		1.5 13 2.8 8.9 4.9 3.0	10 23 10 13	ns ns nC nC nC
Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Charge Gate to Drain "Miller" Charge	$V_{GS} = 10 \text{ V}, $		1.5 13 2.8 8.9 4.9	10 23 10 13	ns ns ns nC nC
Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Charge	$V_{GS} = 10 \text{ V}, $		1.5 13 2.8 8.9 4.9 3.0 2.0	10 23 10 13 7	ns ns nC nC nC
Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Charge Gate to Drain "Miller" Charge	$V_{GS} = 10 \text{ V}, $		1.5 13 2.8 8.9 4.9 3.0	10 23 10 13	ns ns nC nC nC
Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Total Gate Charge Gate to Source Charge Gate to Drain "Miller" Charge rce Diode Characteristics	$V_{GS} = 10 \text{ V}, $		1.5 13 2.8 8.9 4.9 3.0 2.0 0.81	10 23 10 13 7 1.3	ns ns nC nC nC
	Temperature Coefficient Static Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Gate Resistance Characteristics	Temperature Coefficient $I_D = 250 \ \mu A$, referenced to $25 \ ^{\circ}C$ Static Drain to Source On Resistance $V_{GS} = 10 \ V$, $I_D = 4.1 \ A$ Static Drain to Source On Resistance $V_{GS} = 6 \ V$, $I_D = 3.3 \ A$ VGS = 10 V, $I_D = 4.1 \ A$, $T_J = 125 \ ^{\circ}C$ Forward Transconductance $V_{DS} = 10 \ V$, $I_D = 4.1 \ A$ CharacteristicsInput CapacitanceOutput CapacitanceQuery CapacitanceGate Resistance	Temperature Coefficient $I_D = 250 \ \mu A$, referenced to $25 \ ^{\circ}C$ Static Drain to Source On Resistance $V_{GS} = 10 \ V$, $I_D = 4.1 \ A$ $V_{GS} = 6 \ V$, $I_D = 3.3 \ A$ $V_{GS} = 10 \ V$, $I_D = 4.1 \ A$, $T_J = 125 \ ^{\circ}C$ Forward Transconductance $V_{DS} = 10 \ V$, $I_D = 4.1 \ A$ Characteristics $V_{DS} = 10 \ V$, $I_D = 4.1 \ A$ Input Capacitance $V_{DS} = 75 \ V$, $V_{GS} = 0 \ V$,Output Capacitance $F = 1 \ MHz$ Gate Resistance $V_{DS} = 10 \ V$, $V_{SS} = 0 \ V$,	Temperature Coefficient $I_D = 250 \ \mu A$, reterenced to $25 \ ^{\circ}C$ -10Static Drain to Source On Resistance $V_{GS} = 10 \ V, \ I_D = 4.1 \ A$ 56.3 $V_{GS} = 6 \ V, \ I_D = 3.3 \ A$ 73.8 $V_{GS} = 10 \ V, \ I_D = 4.1 \ A, \ T_J = 125 \ ^{\circ}C$ 107Forward Transconductance $V_{DS} = 10 \ V, \ I_D = 4.1 \ A$ 11CharacteristicsInput Capacitance $V_{DS} = 75 \ V, \ V_{GS} = 0 \ V, \ f = 1 \ MHz$ 570Output Capacitance $f = 1 \ MHz$ 2.9Gate Resistance0.5	Temperature Coefficient $I_D = 250 \ \mu A, referenced to 25 \ ^{\circ}C$ -10 Static Drain to Source On Resistance $V_{GS} = 10 \ V, \ I_D = 4.1 \ A$ 56.3 67 Static Drain to Source On Resistance $V_{GS} = 6 \ V, \ I_D = 3.3 \ A$ 73.8 98 $V_{GS} = 10 \ V, \ I_D = 4.1 \ A, \ T_J = 125 \ ^{\circ}C$ 107 126 Forward Transconductance $V_{DS} = 10 \ V, \ I_D = 4.1 \ A$ 11 Characteristics Input Capacitance $V_{DS} = 75 \ V, \ V_{GS} = 0 \ V, \ f = 1 \ MHz$ 570 760 Output Capacitance $V_{DS} = 75 \ V, \ V_{GS} = 0 \ V, \ f = 1 \ MHz$ 64 85 Reverse Transfer Capacitance 0.5 0.5 Characteristics 0.5 0.5

2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty cycle < 2.0%. 3. Starting T_J = 25 °C, L = 1 mH, I_{AS} = 9 A, V_DD = 135 V, V_{GS} = 10 V.

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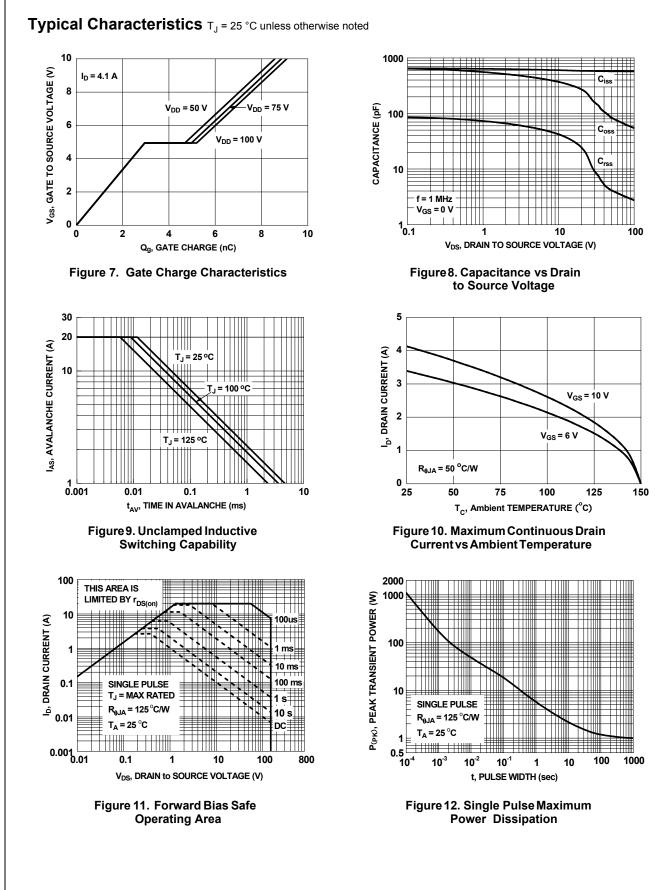
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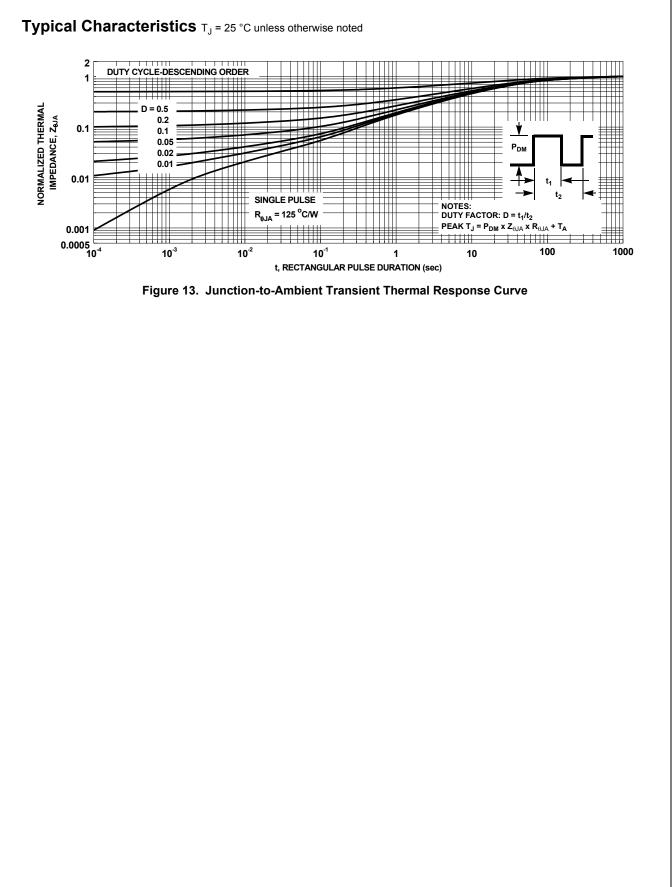
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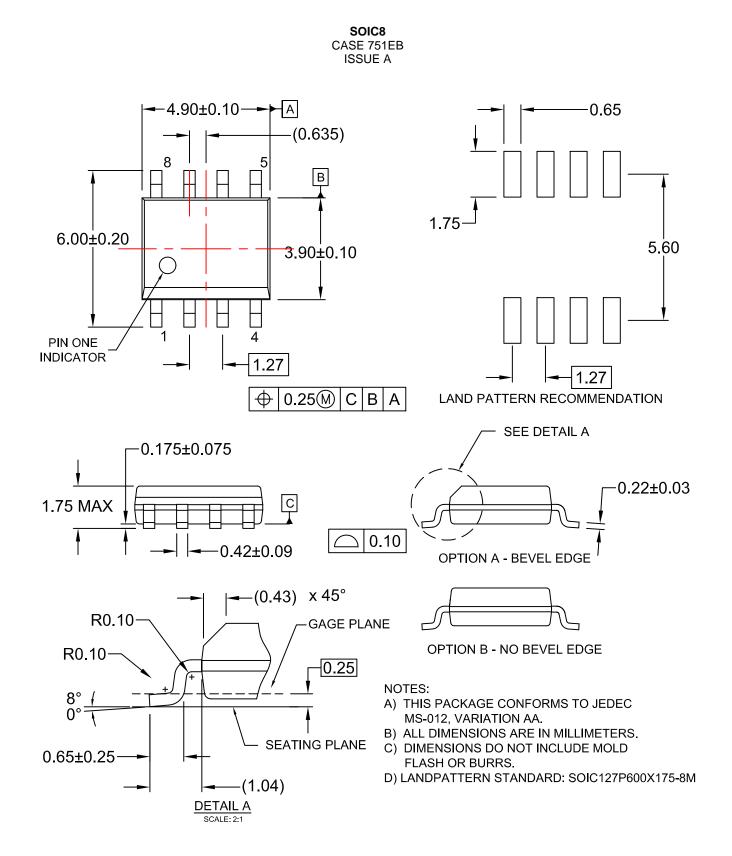




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